

Search Notes

Application/Control No.

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Examiner

Benjamin P. Geib

Applicant(s)/Patent under
Reexamination

THEIS, JEAN-PAUL

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
712	225	10/2/2006	BPG

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	10/2/2006	BPG
Google Scholar Search	10/2/2006	BPG